# Mechanical loss studies at Maastricht University

# V.Spagnuolo<sup>1,2\*</sup>, S.Gouvalas<sup>1</sup>, I.W.Martin<sup>3</sup>, G.McGhee<sup>3</sup>, P.Murray<sup>3</sup>, S.Tait<sup>3</sup>, C.Clark<sup>4</sup>, Nena Mavridi<sup>4</sup>, S.Hild<sup>1,2</sup>, and J.Steinlechner<sup>1,2,3</sup>

<sup>1</sup>Maastricht University, P.O. Box 616, 6200 MD Maastricht, The Netherlands, <sup>2</sup>Nikhef Institute, Science Park 105, 1098 XG Amsterdam, The Netherlands <sup>3</sup>Institute for Gravitational Research, SUPA School of Physics and Astronomy, University of Glasgow, Scotland, <sup>4</sup>Helia Photonics, Rosebank Technology Park Unit 2, Livingston, EH54 7EJ, Scotland

## \*v.spagnuolo@maastrichtuniversity.nl

## 1. Motivation

Maastricht University

For current gravitational wave interferometers, the limit in sensitivity at their most sensitive frequencies originates from the thermal noise, dominated by the loss angle of high refractive index material. As part of a new coating characterization laboratory at Maastricht University, a gentle nodal suspension system has been built. We will present initial studies of the mechanical loss of different compositions of TiO<sub>2</sub> doped with a few percent of GeO<sub>2</sub> as part of a comprehensive study of the effect of composition and heat treatment on loss and absorption of magnetron-sputtered germania-based coatings.

## 2. Gentle Nodal Suspension (GeNS) system

- GeNS system: the sample is suspended on the top of spherical surface, inside the vacuum tank [1].
- Only applied force is its weight, no external damping.
- A non-contacting electrostatic actuator can excite the characteristic mode vibrations of the sample.



Fig. 1. Photo of out GeNS setup.

# 2.1 the Samples

• 2x PIAD EBE (electron beam evaporation) coatings made by Helia Photonics:

1. 85% TiO<sub>2</sub> and 15% GeO<sub>2</sub> 2. 95% TiO<sub>2</sub> and 5% GeO<sub>2</sub>

• for reference: 3x uncoated SiO<sub>2</sub> substrates 50mm x 1mm, heat treated @ 900° for 4hrs.



Fig. 2. Fused silica disk.

# **3. Uncoated Loss**

- Test for the repeatability of GeNS.
- Characterization of SiO<sub>2</sub> substrates of same geometry of the coated germania samples.
- Visible trend of the loss angle <sup>≤</sup> as a function of the modes family for each disk.
- Mean value for the loss angle at  $(2.2 \pm 1.0) \times 10^{-7}$ .

## **5. Results**

- Previous studies on ZrO<sub>2</sub>:Ta<sub>2</sub>O<sub>5</sub> and heattreatment showed the mechanical loss correlated with fraction of corner sharing in 🖉 10 the amorphous structure [2].
- Loss level of coated disks very consistent for all the modes.
- Lower loss of 15% Ge-doped Ti coating due to different layer thickness  $\rightarrow$  cancel out after the analysis
- 5% Ge-doped Ti as-deposited give loss angle at  $8.8 \times 10^{-4} \pm 2.0 \times 10^{-7}$ .
- 15% Ge-doped Ti as-deposited give loss angle at  $9.1 \times 10^{-4} \pm 3.1 \times 10^{-7}$ .





Fig. 3. Summary of all measurements on the uncoated SiO<sub>2</sub> samples.



Fig. 6. (top) Coating loss angle of mixed GeO<sub>2</sub> samples. (bottom) Comparison between uncoated, coated and coating loss for 85% and 95% in TiO<sub>2</sub>.

# 4. Energy Ratio



#### Fig. 4. Energy ratio as function of different frequency for the two different TiO<sub>2</sub>:GeO<sub>2</sub> coated samples.

Coating sample	Thickness	Young modulus	Poisson ratio	
85% TiO2:GeO2	395 [nm]	138.8 [GPa]	0.27	Fig.5. S shape: the m
95% TiO2:GeO2	650 [nm]	149.4 [GPa]	0.28	

# 6. Current status and next step

#### Done:

- Characterization of uncoated SiO<sub>2</sub> substrates.
- Mechanical loss measurement of 85% and 95% TiO<sub>2</sub>:GeO<sub>2</sub> as-deposited.

## To do:

- Explore the effect of heat treatment on the same doped samples.
- Further investigations on germania doped titania samples in different concentration and different geometry.

## **References:**

[1] E.Cesarini et al., "A 'gentle' nodal suspension for measurements of the acoustic attenuation in materials", Rev. Sci. Instrum. 80, 053904 (2009).

[2] K. Prasai et al., "High Precision Detection of Change in Intermediate Range Order of Amorphous Zirconia-Doped Tantala Thin Films Due to Annealing", Phys. Rev. Lett. 123, 045501, (2019).

